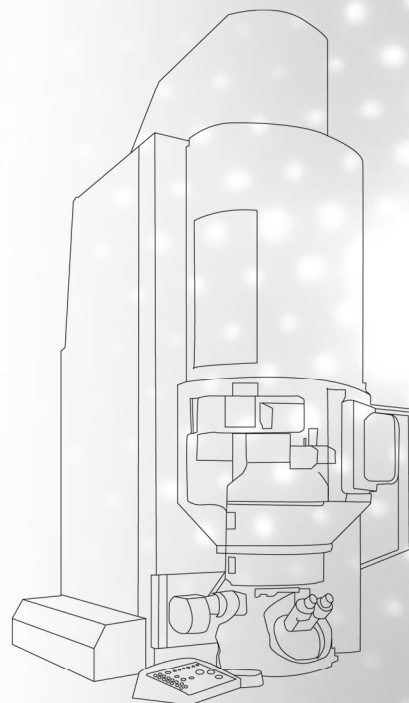


Nanomegas 3D ED/MicroED Solutions and Recent Advances in Precession- Assisted Serial Electron Diffraction

Dr. Partha Pratim Das

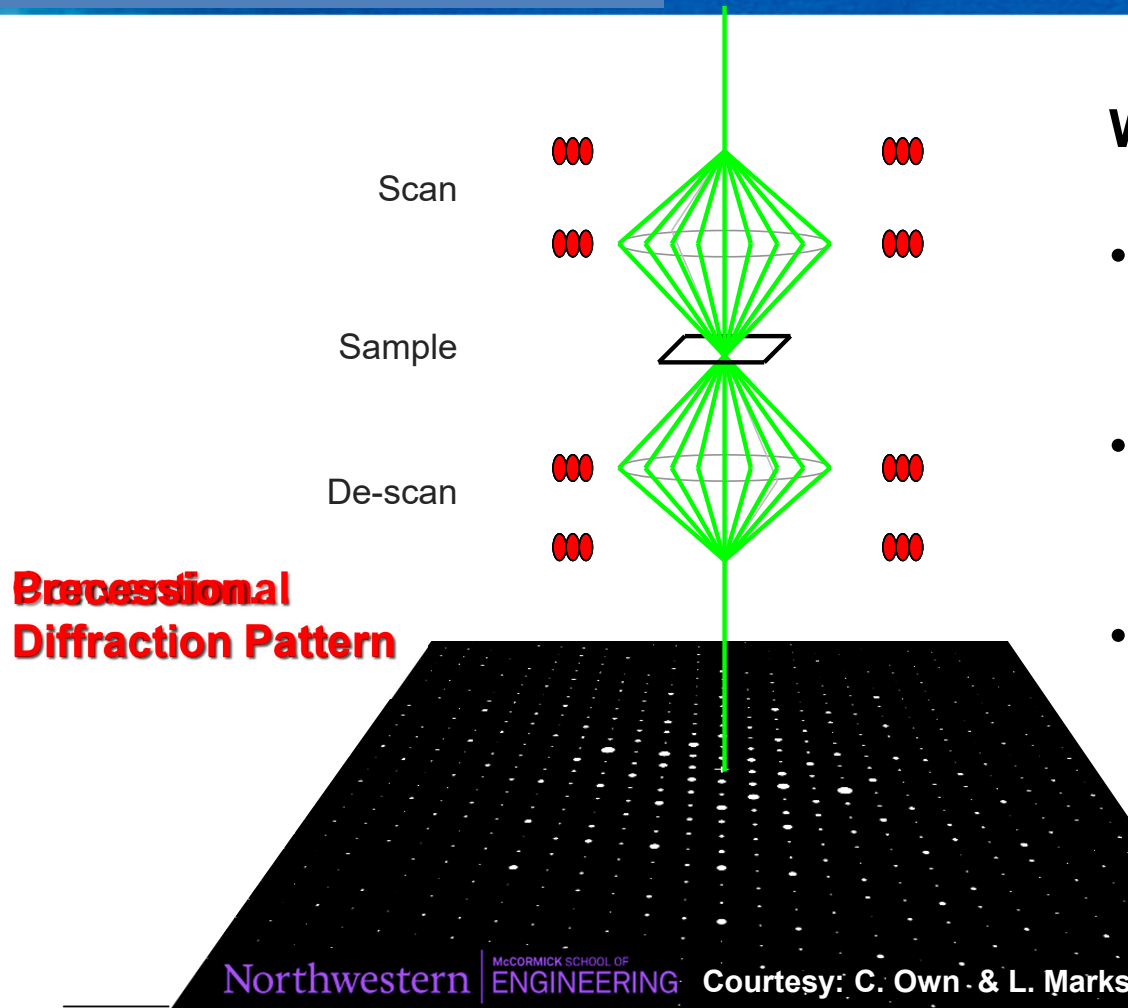
Application Specialist, Nanomegas SPRL, Belgium

partha@nanomegas.com



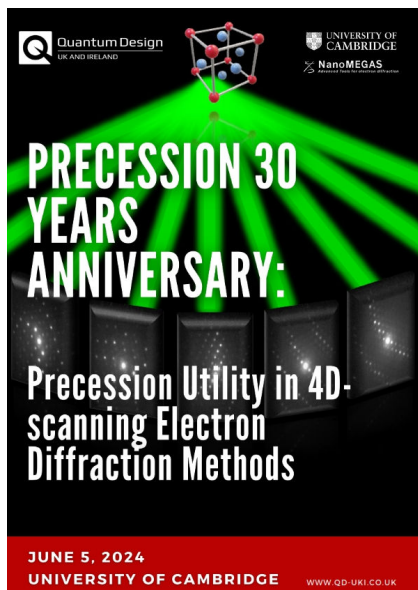
MicroED Short Course
November 3-5, 2025

Precession Electron Diffraction



With Precession:

- **Higher resolution**
Access to higher order reflections
- **Reduction of dynamical effect**
Close to kinematical reflections
- **Less sensitivity to specimen thickness / bending**

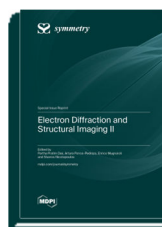


Established in 2004 in Brussels, Belgium: Electron Diffraction Solutions for TEM



> 1000 articles in 21 years based on the provided solutions

Scientific and Research Activities



Special Issue On Electron Diffraction
19 Invited Articles

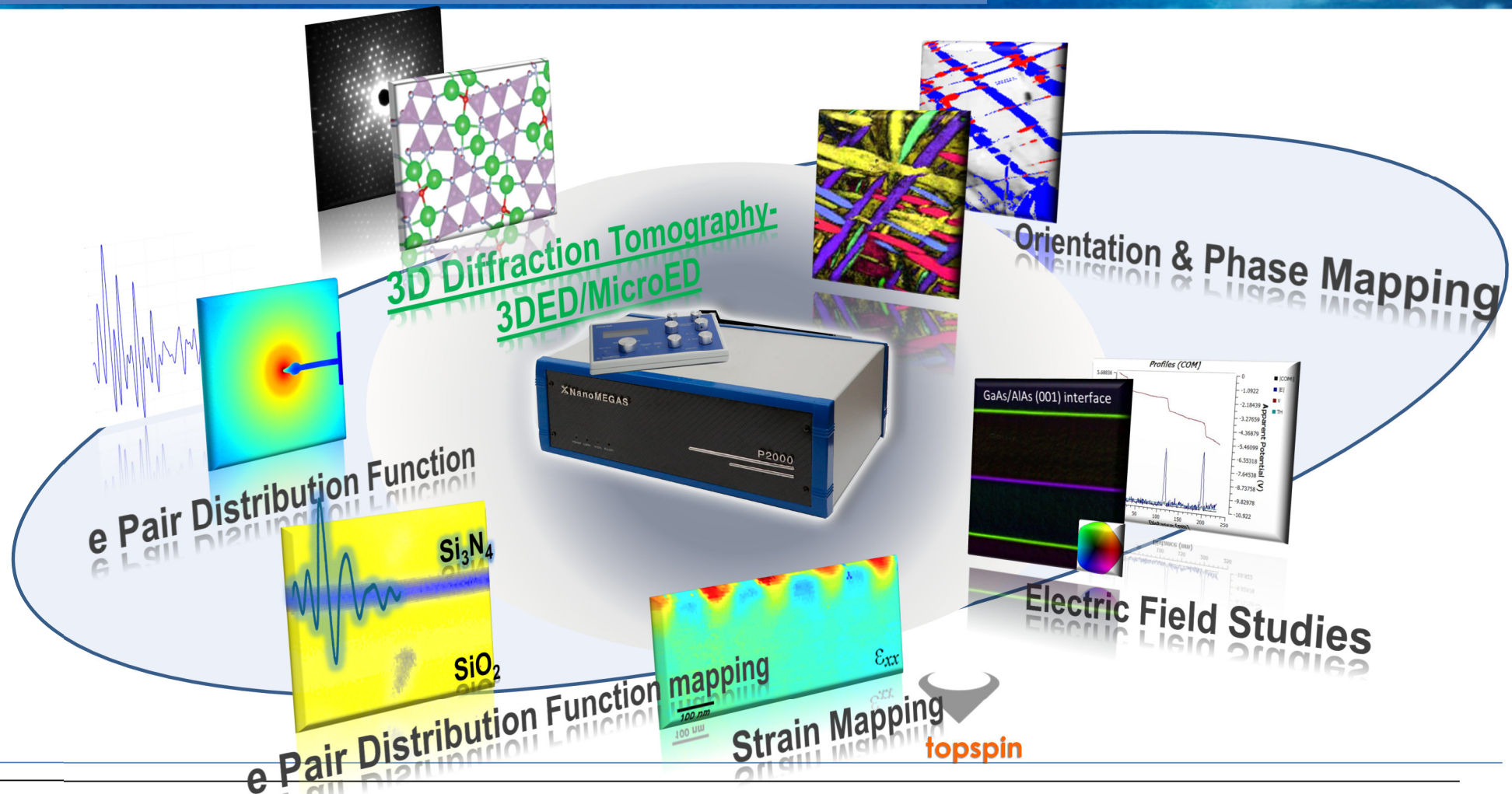
Innovative electron diffraction solutions for amorphous
materials and electrochemistry

Partner

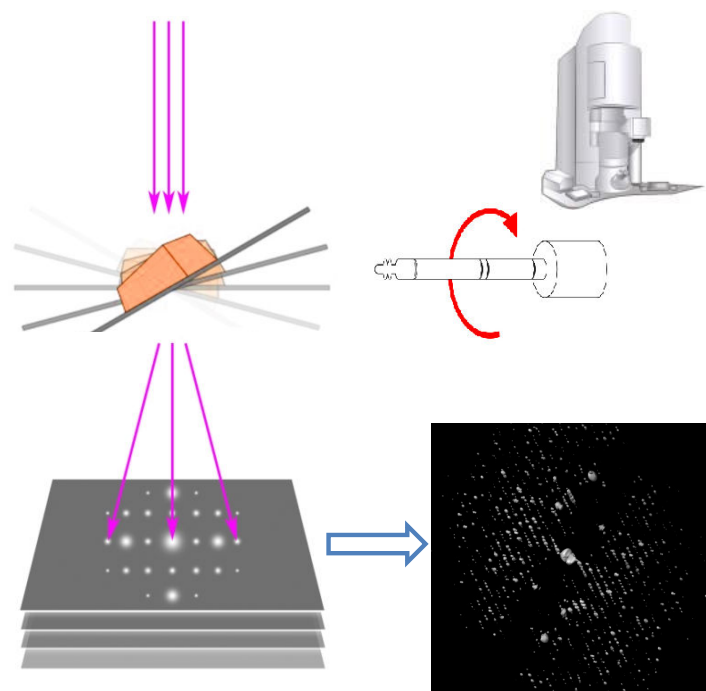
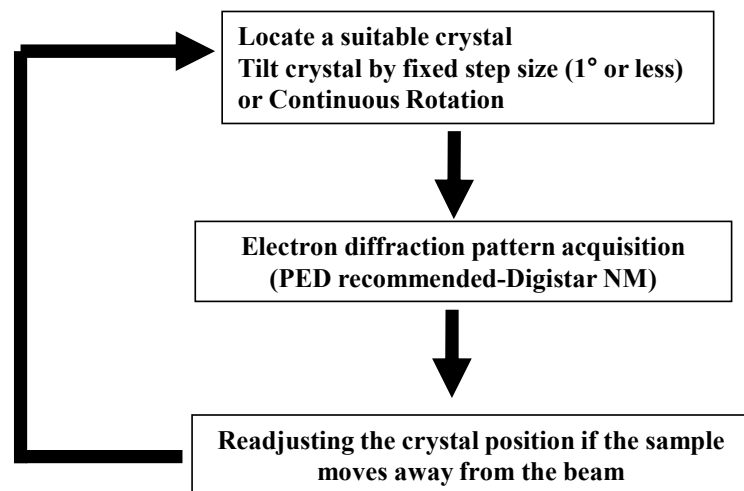


www.nanomegas.com

NanoMEGAS Electron Diffraction Solutions – 330+ installations



3D ED Data Acquisition in TEM



ADT U. Kolb et al., *Ultramicroscopy* 107, 507-513 (2007)

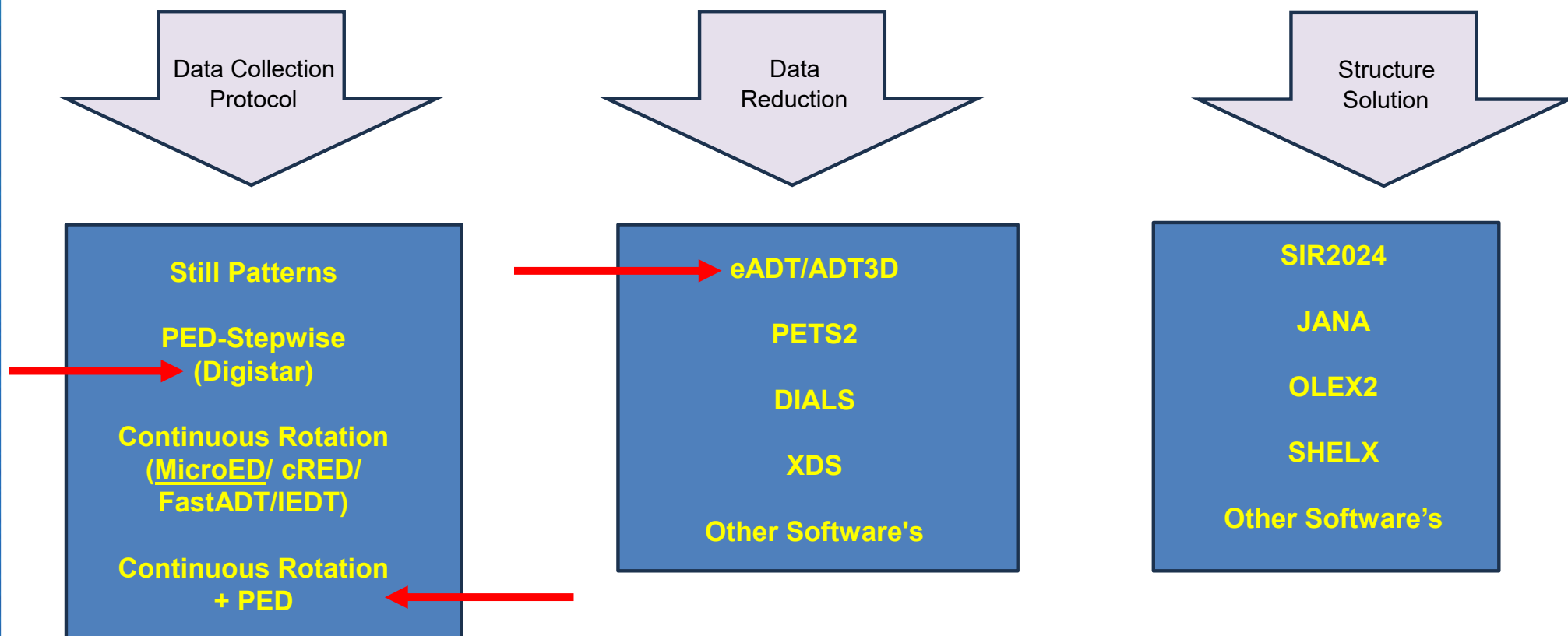
PEDT Mugnaioli et al., *Ultramicroscopy* 109, 758-765 (2009)

Micro-ED/ cRED/ FADT/ IEDT Nederlof et al., *Acta Crystallogr. D* 69, 1223-1230 (April, 2013); Shi et al. *eLife* eLife01345 (Nov, 2013)

ACS Cent. Sci. 2019, 5, 1315-1329

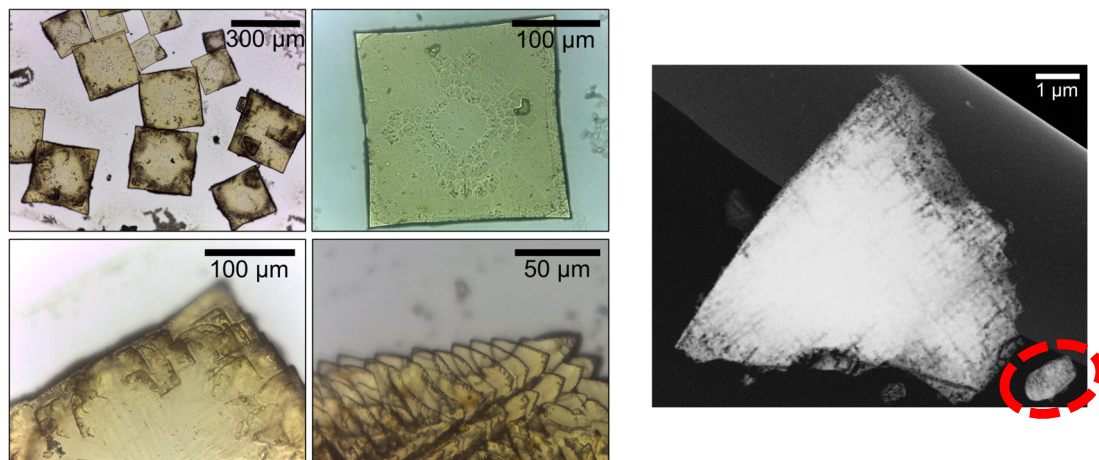
3D ED/Micro ED

Data Collection to Structure Solution Where NM Solution Helps



One Example Among Many Structures Solved with Stepwise Precession Assisted 3DED

Structure of Orthocetamol ($C_8H_9NO_2$)- Its structure was still unknown in 2019!



The Crystal Structure of Orthocetamol Solved by 3D Electron Diffraction.
Andrusenko et al. *Angew Chem Int Ed* **58**, 10919 (2019).

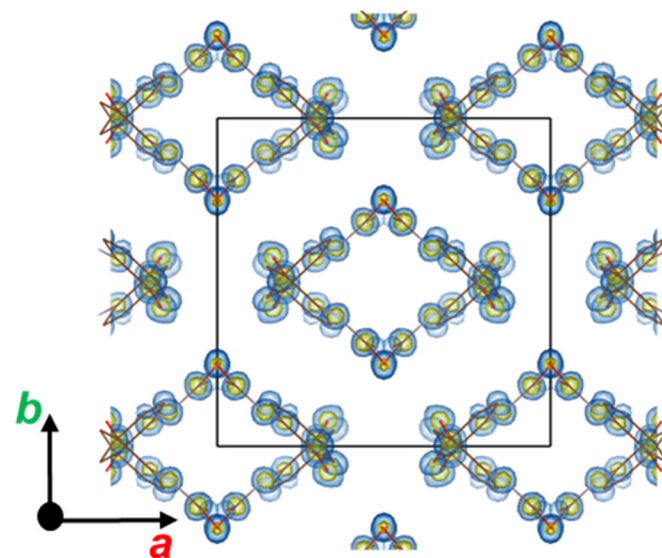
Resolution = 0.9 Å, Coverage (ind. refl.) = 97%, $R_{\text{int}}(F) = 28.45\%$

Kinematical refinement converged at $R1(4\sigma) = 37.31\%$

After the introduction of a rotational **twinning** that exchanges a and b , refinement converged at $R1(4\sigma) = 32.70\%$
(twinning contribution 34%)

$$a = 10.56 \text{ \AA}, b = 10.39 \text{ \AA}, \\ c = 13.72 \text{ \AA}, \beta = 93.11^\circ$$

$C2/c$



*Stepwise PED was used for data acquisition due to the small domain size.
The twinned domains are smaller than the 150 nm diameter beam used for 3D ED data acquisition*

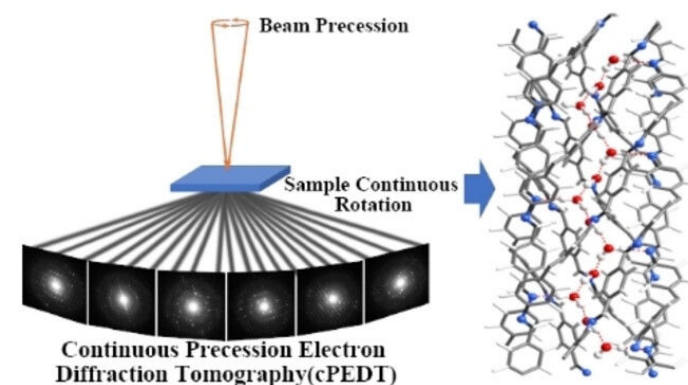
Combination of PED + Continuous Rotation – Example 1

Locating Hydrogen Positions for COF-300 by Cryo-3D Electron Diffraction

Sun *et al.* (*Angew Chem. Int. Ed.*, 2023)

Comparison of the data collected between Continuous Rotation + PED VS Continuous Rotation Only

Particle name	The type of data collection	R_{int} / %	The number of hydrogen atoms found	R_1 value / %
1	cPEDT	15.39	7	19.87
	cRED	27.83	7	20.28
2	cPEDT	14.87	6	22.52
	cRED	16.44	5	22.55
3	cPEDT	27.30	3	21.92
	cRED	38.62	3	26.39
4	cPEDT	43.02	1	31.87
	cRED	49.26	1	27.60
5	cPEDT	22.33	5	25.30
	cRED	43.34	3	29.30



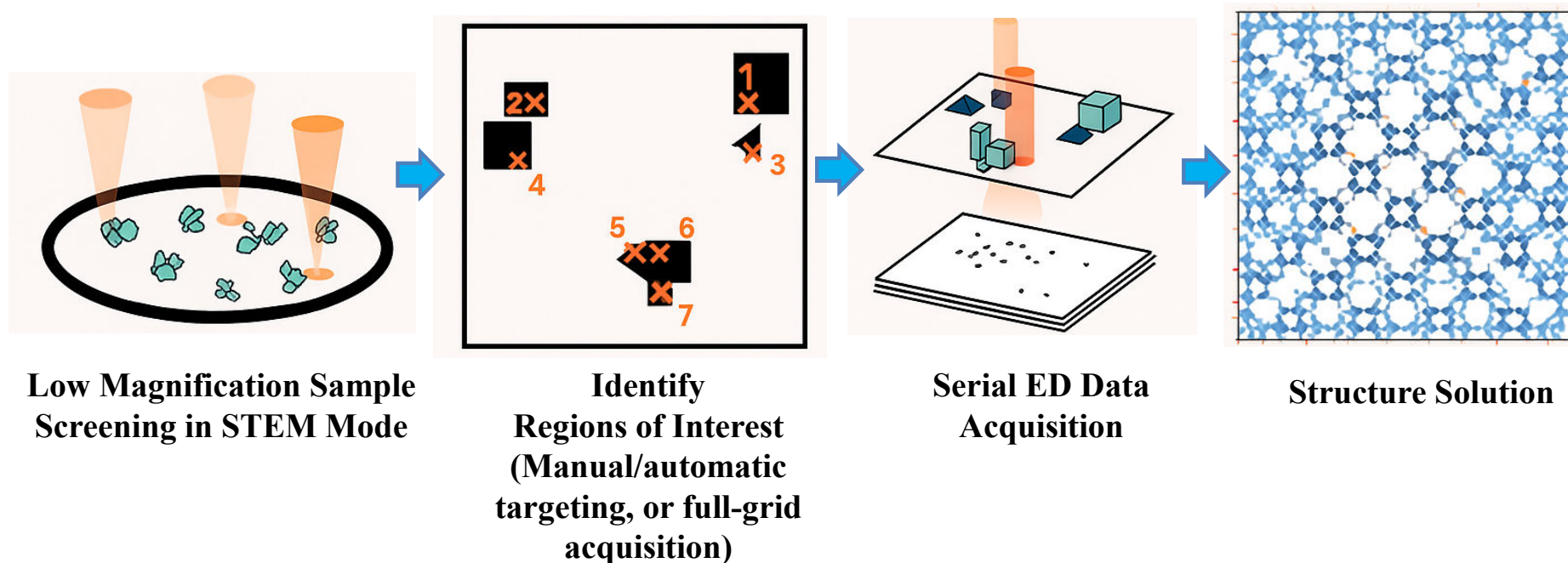
Lower R_{int} , More No of H atoms found during Kinematic refinement, Lower Refined R value with Continuous Rotation + PED data

Combination of PED + Continuous Rotation – Example 2

Crystal	10			07			13			09		11		12	
				Continuous Rotation + PED VS Continuous Rotation											
Acquisition Method	Cont	Prec&Cont	Prec&Cont	Cont	Prec&Cont	Prec&Cont	Cont	Prec&Cont	Prec&Cont	Prec&Cont	Prec&Cont	Prec&Cont	Prec&Cont	Prec&Cont	Prec&Cont
Integration Method	Profile fit	Profile fit	Integration	Profile fit	Profile fit	Integration	Profile fit	Profile fit	Integration	Profile fit	Integration	Profile fit	Integration	Profile fit	Integration
Tilt range (°)	109	122		114	97		118	120		112		103		96	
N. of stitched tilt series	3	2		3	2		2	4		2		2		1	
Cell Parameter a (Å)	26.85(1)	26.62(1)		26.77(1)	26.74(1)		26.816(1)	26.721(1)		26.77(1)		26.736(1)		26.866(1)	
Cell Parameter c (Å)	7.553(4)	7.652(3)		7.538(5)	7.589(3)		7.601(5)	7.618(3)		7.587(3)		7.633(3)		7.622(5)	
N. reflections	12926	18701	18784	17148	15033	15319	17579	17972	18289	17151	17455	15239	15504	14104	14374
N. independent reflections	6038	6825	6832	6185	6096	6211	7352	7376	7415	6067	6186	6918	6986	6022	6138
N. reflecton > 2σ	507	3178	5539	998	2663	4811	1109	1280	3072	2912	5021	2352	3900	1556	2613
R _{int}	1.0831	0.3164	0.2690	0.5957	0.2766	<u>0.2629</u>	0.6955	0.5874	0.3926	0.4186	0.3816	0.3682	0.3321	0.3952	0.4026
R1(all)	0.7256	0.4200	0.3847	0.5667	0.4759	0.4018	0.6170	0.5835	0.4881	0.5206	0.4482	0.5093	0.4330	0.5039	0.4528
R1(obs)	0.6565	0.3375	0.3716	0.3492	0.4216	0.3882	0.4905	0.3944	0.4108	0.4898	0.4404	0.4119	0.3686	0.3719	0.3652
wR2(all)	0.8863	0.6221	0.6477	0.7188	0.6802	0.6661	0.8053	0.7319	0.7095	0.7334	0.7006	0.6995	0.6650	0.7171	0.6955
wR2(obs)	0.8185	0.5865	0.6389	0.6225	0.6520	0.6477	0.7324	0.6473	0.6729	0.7162	0.6954	0.6548	0.6386	0.6573	0.6471
Atoms (C,N) found ab-initio	no solution	20	20	no solution	no solution	18	no solution	no solution	17	no solution	no solution	19	20	no solution	19

It is considered the structure is solved when one can recognize most of the C and N atoms (total 20). Group of 10 B atoms is difficult to recognize ab-initio and it is very distorted, so it was not used as a criteria. (To be Published Das et al.)

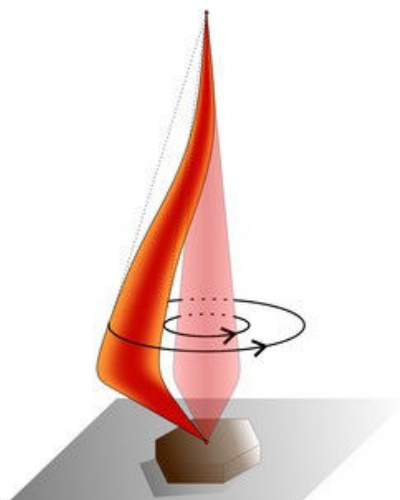
A New Method For Data Collection and Structure Solution - Serial Electron Diffraction



Smeets et al., J Appl Cryst, 2018, Bücker et al., Nature Commun. 2020, Hogan-Lamarre et al., IUCrJ, 2024

New Trend - Precession-Assisted Serial Electron Diffraction

- **Precession** can help achieve better **integration of reflections**
- It **reduces dynamical effects**, leading to more reliable intensity measurements
 - This enables **structure analysis with fewer diffraction patterns**
- It may also allow **dynamical refinement** for improved structural accuracy



 JOURNAL OF
APPLIED
CRYSTALLOGRAPHY
ISSN 1600-5767

Received 14 April 2025
Accepted 20 June 2025

On the use of beam precession for serial electron crystallography

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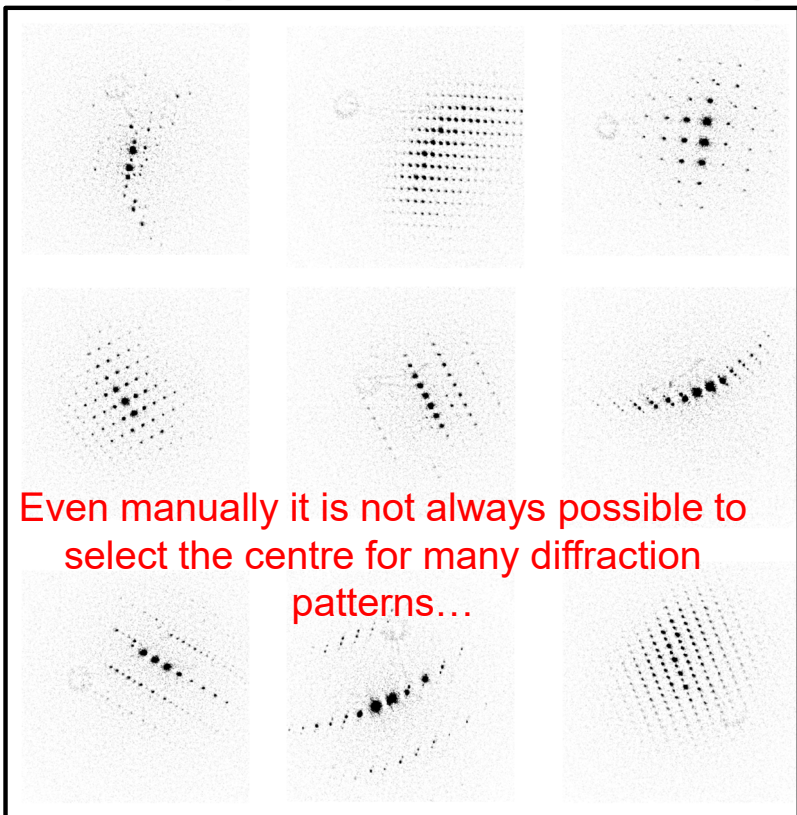
^aServei de Recursos Científics i Tècnics, Universitat Rovira i Virgili, Avinguda Països Catalans 26, Tarragona, Catalonia 43007, Spain, ^bLENS-MIND, Department of Electronics and Biomedical Engineering, Universitat de Barcelona, Martí i Franquès 1, Barcelona, Catalonia 08028, Spain, and ^cErnst Ruska-Centre for Microscopy and Spectroscopy with Electrons, Forschungszentrum Jülich, Wilhelm-Johnen-Strasse, Jülich 52425, Germany. *Correspondence e-mail: sergi.plana@urv.cat

A Case Study – Carbamazepine – Precession Assisted Serial ED

Serial ED Carbamazepine

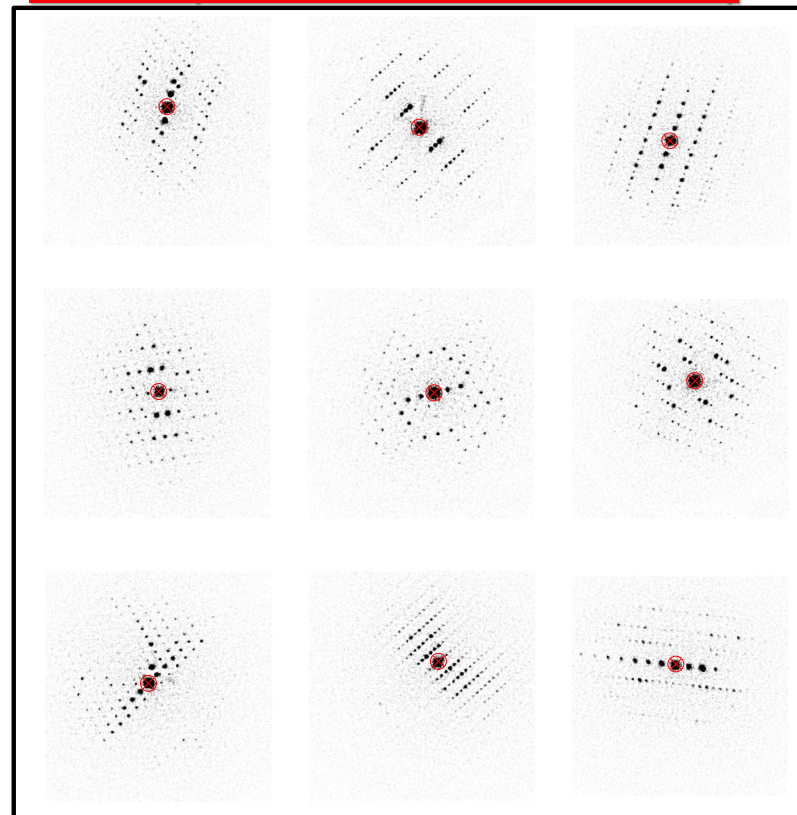
Ongoing Collaboration Work with Enrico
Mugnaioli and Iryna Andrusenko - University of
Pisa, Italy

NO PED (1011 Patterns – 573 used)



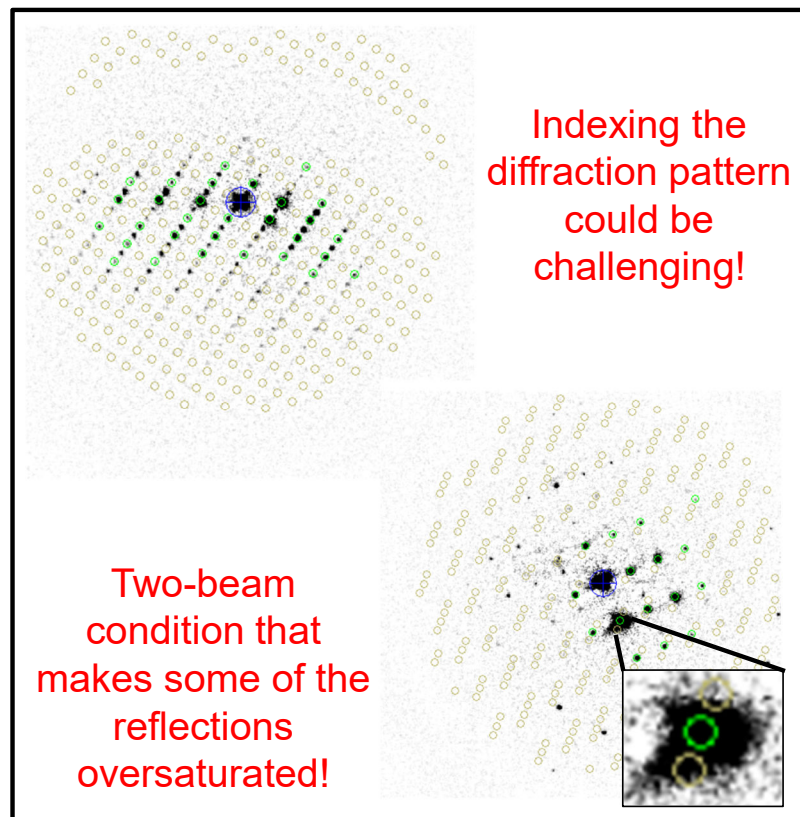
Serial ED Carbamazepine

PED 1° (1005 Patterns – 573 used)

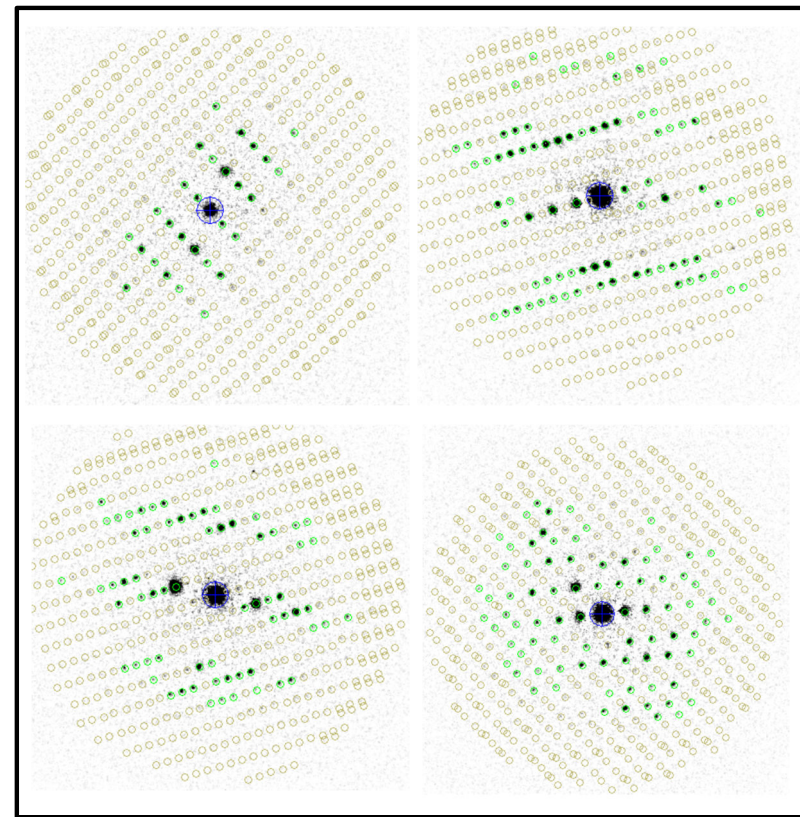


A Case Study – Carbamazepine – Precession Assisted Serial ED

Serial ED Carbamazepine **NO PED**



Serial ED Carbamazepine **PED 1°**



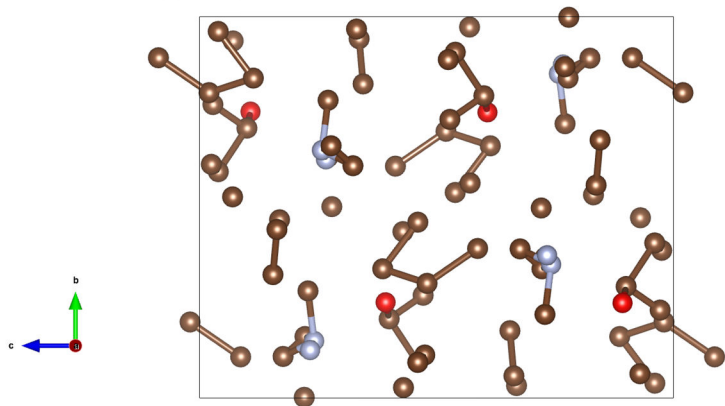
A Case Study - Carbamazepine – Precession Assisted Serial ED

Serial ED
Carbamazepine
NO PED

Ab-initio structure solution in $P2_1/n$

Res 1.0 Å
 R_{int} 32.89 %

No structure solution at all!

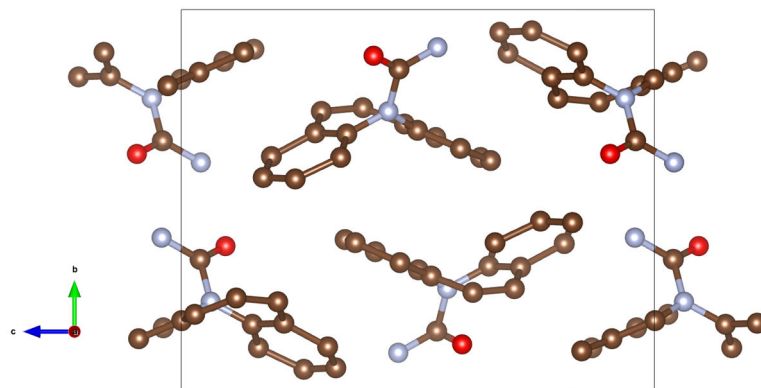


Serial ED
Carbamazepine
PED 1°

Ab-initio structure solution in $P2_1/n$

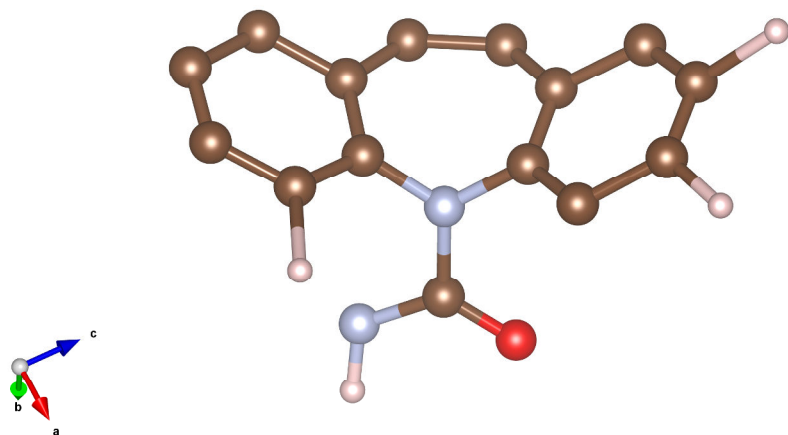
Res 1.0 Å
 R_{int} 13.60 %
Completeness 94%
 $u(\text{iso})$ 0.00865 Å²
Final R 21.80%

Just perfect!



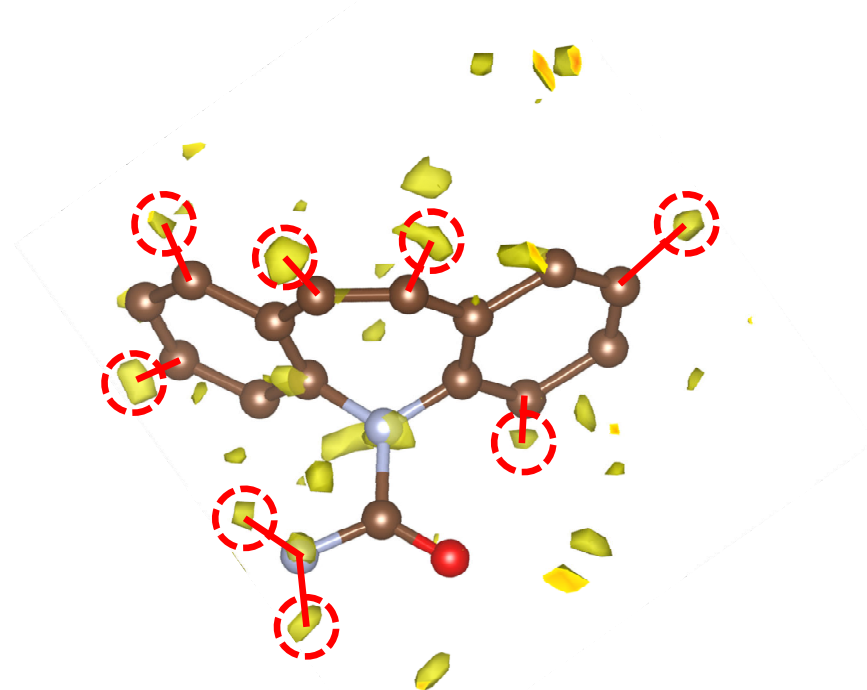
A Case Study - Carbamazepine – Precession Assisted Serial ED

High Quality Structure – Precession Assisted Serial ED



4 hydrogen atoms are spotted
in the *ab-initio* solution

Ongoing Collaboration Work with Enrico
Mugnaioli and Iryna Andrusenko - University of
Pisa, Italy



8 hydrogen atoms are determined from the first
difference Fourier map, without performing any
refinement

Conclusions:

1. NanoMEGAS provides a precession system where the precession angle can be varied over a wide range, depending on the application, and operated at high frequencies.
2. The precession mode can be used for both stepwise 3DED and continuous 3DED experiments.
3. The NanoMEGAS precession and scanning synchronization system, integrated with many popular camera (CCD, CMOS and Direct Electron Detector e.g. QD, ASI, Dectris, Direct Electron etc..) platforms, enables precession assisted 4D-STEM applications.
4. We are developing precession assisted Serial Electron Diffraction (Serial ED) for high-quality structure determination of beam-sensitive materials.



Photo from NanoMEGAS annual meeting, Brussels, June 2025

Thanks for your attention !!!



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RAVE SCIENTIFIC
SERVING SCIENCE AND INDUSTRY



Jeff Streger
Principal



Lisa Streger
Manager of Operations



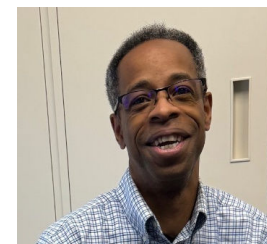
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EM Sales, Service &
Applications



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Accounting Specialist



Jason Josiah
Shipping and Logistics



NanoMEGAS

Advanced Tools for electron diffraction

www.nanomegas.com

**Serial ED
Carbamazepine
PED 1°**

Manual data collection in STEM mode
CL 250 (resolution in real space up to 0.7Å)

PED 1°

Total **1005** frames

Exposition time 200 ms / frame

Acquisition time – half day

Size 0.99 GB

Used **573** frames

**Serial ED
Carbamazepine
NO PED**

Manual data collection in STEM mode
CL 250 (resolution in real space up to 0.7Å)

NO PED

Total **1011** frames

Exposition time 200 ms / frame

Acquisition time – half day

Size 0.99 GB

Used **573** frames